

TMOS IV Power Field Effect Transistor N-Channel Enhancement-Mode Silicon Gate

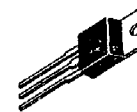
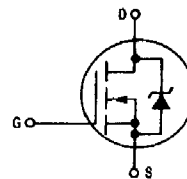
This advanced "E" series of TMOS power MOSFETs is designed to withstand high energy in the avalanche and commutation modes. These new energy efficient devices also offer drain-to-source diodes with fast recovery times. Designed for low voltage, high speed switching applications in power supplies, converters and PWM motor controls, these devices are particularly well suited for bridge circuits where diode speed and commutating safe operating area are critical, and offer additional safety margin against unexpected voltage transients.

- Internal Source-to-Drain Diode Designed to Replace External Zener Transient Suppressor — Absorbs High Energy in the Avalanche Mode — Unclamped Inductive Switching (UIS) Energy Capability Specified at 100°C.
- Commutating Safe Operating Area (CSOA) Specified for Use in Half and Full Bridge Circuits
- Source-to-Drain Diode Recovery Time Comparable to a Discrete Fast Recovery Diode
- Diode is Characterized for Use in Bridge Circuits



MTP25N05E

TMOS POWER FETs
25 AMPERES
 $r_{DS(on)} = 0.07 \text{ OHM}$
50 VOLTS



TO-220AB

MAXIMUM RATINGS ($T_J = 25^\circ\text{C}$ unless otherwise noted)

Rating	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	50	Vdc
Drain-Gate Voltage ($R_{GS} = 1 \text{ M}\Omega$)	V_{DGR}	50	Vdc
Gate-Source Voltage — Continuous	V_{GS}	± 20	Vdc
— Non-repetitive ($t_p \leq 50 \mu\text{s}$)	V_{GSM}	± 40	Vpk
Drain Current — Continuous	I_D	25	Adc
— Pulsed	I_{DM}	80	
Total Power Dissipation @ $T_C = 25^\circ\text{C}$	P_D	100	Watts
Derate above 25°C		0.8	W/°C
Operating and Storage Temperature Range	T_J, T_{stg}	-65 to 150	°C

THERMAL CHARACTERISTICS

Thermal Resistance — Junction to Case	$R_{\theta JC}$	1.25	°C/W
— Junction to Ambient	$R_{\theta JA}$	62.5	
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 5 seconds	T_L	275	°C

Designer's Data for "Worst Case" Conditions — The Designer's Data Sheet permits the design of most circuits entirely from the information presented. SOA Limit curves — representing boundaries on device characteristics — are given to facilitate "worst case" design.



NJ Semi-Conductors reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by NJ Semi-Conductors is believed to be both accurate and reliable at the time of going to press. However, NJ Semi-Conductors assumes no responsibility for any errors or omissions discovered in its use. NJ Semi-Conductors encourages customers to verify that datasheets are current before placing orders.

MTP25N05E

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit	
OFF CHARACTERISTICS					
Drain-Source Breakdown Voltage (V _{GS} = 0, I _D = 0.25 mA)	V _{(BR)DSS}	50	—	Vdc	
Zero Gate Voltage Drain Current (V _{DS} = Rated V _{DSS} , V _{GS} = 0) (V _{DS} = Rated V _{DSS} , V _{GS} = 0, T _J = 125°C)	I _{DSS}	—	10 100	μA	
Gate-Body Leakage Current, Forward (V _{GSF} = 20 Vdc, V _{DS} = 0)	I _{GSSF}	—	100	nAdc	
Gate-Body Leakage Current, Reverse (V _{GSR} = 20 Vdc, V _{DS} = 0)	I _{GSSR}	—	100	nAdc	
ON CHARACTERISTICS*					
Gate Threshold Voltage (V _{DS} = V _{GS} , I _D = 250 μA, T _J = 100°C)	V _{GS(th)}	2 1.5	4 3.5	Vdc	
Static Drain-Source On-Resistance (V _{GS} = 10 Vdc, I _D = 16 Adc)	r _{DS(on)}	—	0.07	Ohm	
Drain-Source On-Voltage (V _{GS} = 10 V) (I _D = 25 Adc) (I _D = 12.5 Adc, T _J = 100°C)	V _{DS(on)}	—	2 1	Vdc	
Forward Transconductance (V _{DS} = 1.75 V, I _D = 16 A)	g _{FS}	9	—	mhos	
DRAIN-TO-SOURCE AVALANCHE CHARACTERISTICS					
Unclamped Drain-to-Source Avalanche Energy See Figures 14 and 15 (I _D = 80 A, V _{DD} = 25 V, T _C = 25°C, Single Pulse, Non-repetitive) (I _D = 25 A, V _{DD} = 25 V, T _C = 25°C, P.W. ≤ 200 μs, Duty Cycle ≤ 1%) (I _D = 10 A, V _{DD} = 25 V, T _C = 100°C, P.W. ≤ 200 μs, Duty Cycle ≤ 1%)	W _{DSSR}	—	90 200 90	mJ	
DYNAMIC CHARACTERISTICS					
Input Capacitance	(V _{DS} = 25 V, V _{GS} = 0, f = 1 MHz) See Figure 16	C _{iss}	—	1800	pF
Output Capacitance		C _{oss}	—	800	
Reverse Transfer Capacitance		C _{rss}	—	200	
SWITCHING CHARACTERISTICS* (T_J = 100°C)					
Turn-On Delay Time	(V _{DD} = 25 V, I _D = 16 A R _{gen} = 15 ohms) See Figure 9	t _{d(on)}	—	25	ns
Rise Time		t _r	—	35	
Turn-Off Delay Time		t _{d(off)}	—	45	
Fall Time		t _f	—	35	
Total Gate Charge	(V _{DS} = 0.8 Rated V _{DSS} , I _D = Rated I _D , V _{GS} = 10 V) See Figures 17 and 18	Q _g	28 (Typ)	30	nC
Gate-Source Charge		Q _{gs}	14 (Typ)	—	
Gate-Drain Charge		Q _{gd}	12 (Typ)	—	
SOURCE DRAIN DIODE CHARACTERISTICS*					
Forward On-Voltage	(I _S = 25 A V _{GS} = 0)	V _{SD}	1.3 (Typ)	1.5	Vdc
Forward Turn-On Time		t _{on}	Limited by stray inductance		
Reverse Recovery Time		t _{rr}	180 (Typ)	—	ns
INTERNAL PACKAGE INDUCTANCE					
Internal Drain Inductance (Measured from the contact screw on tab to center of die) (Measured from the drain lead 0.25" from package to center of die)	L _d	3.5 (Typ) 4.5 (Typ)	—	—	nH
Internal Source Inductance (Measured from the source lead 0.25" from package to source bond pad.)	L _s	7.5 (Typ)	—	—	

*Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.